

Tip Scanning Z/ Probe Holder

Model ID: ▶ TS-Z6
▶ TS-Z16

AFMWorkshop's tip scanning

atomic force microscopes include the SA-AFM, the NP-AFM, and the LS-AFM. These systems all use an independent Z piezoelectric ceramic/probe holder module. AFMWorkshop offers two probe holders for tip-scanning atomic force microscopes that are interchangeable and designed for different applications.



Both Z probe holders include a probe exchange guide which facilitates probe exchanges. To exchange probes, the probe module is simply placed on top of the exchange guide, light pressure is applied, the guide then releases the probe clamping spring, and the probe is then easily exchanged.

▶ TS-Z6



The TS-Z6 module is designed for making low noise measurements with the SA and NP units. With a Z range of 7 μm and specified noise floor of 0.12 nm, it is ideal for nano-roughness measurements.

▶ TS-Z16



The TS-Z16 module is designed for general AFM applications, and for applications requiring force distance curves. Applications include life sciences, material sciences, and technical applications that do not need the ultimate noise floor.

MODEL	Z RANGE	NOISE FLOOR*	STRAIN GAUGE	APPLICATIONS
TS-Z6	>7 μm	0.12 nm	No	Low Noise
TS-Z16	>16 μm	0.20 nm	Yes	General Scanning

**Obtaining the specified noise floor requires a controlled vibration environment. Specifications are demonstrated on each module at the AFMWorkshop factory prior to shipment.*